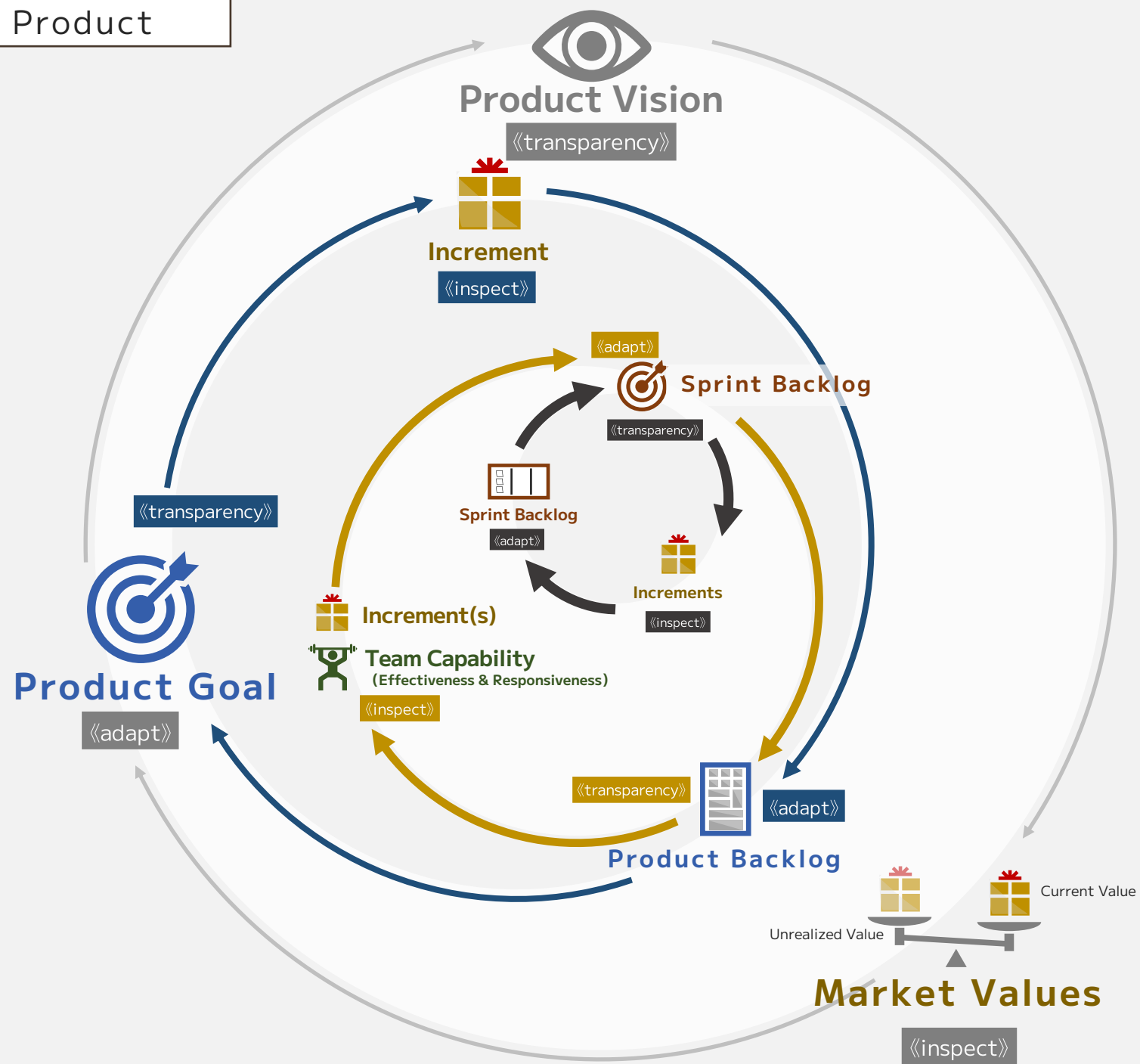


Inspect & Adapt for Product

variation II



Special thanks for Stefan Dreverman